

Notice of References Cited	Application/Control No. 10/723,350	Applicant(s)/Patent Under Reexamination MARTIN ET AL.	
	Examiner Rip A. Lee	Art Unit 1713	Page 1 of 1

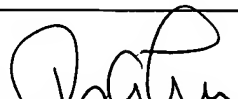
U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,107,230 A	08-2000	McDaniel et al.	502/104
	B	US-5,326,837 A	07-1994	Kissin, Yury V.	526/150
	C	US-4,978,730	12-1990	Maezawa et al.	526/153
	D	US-6,825,369 B1	11-2004	Stevens et al.	556/7
	E	US-6,410,657 B1	06-2002	Ko et al.	525/338
	F	US-6,271,322 B1	08-2001	McCullough et al.	526/160
	G	US-6,159,889 A	12-2000	Wasserman, Eric Paul	502/125
	H	US-6,020,439 A	02-2000	Ko et al.	525/338
	I	US-5,962,362 A	10-1999	Wasserman et al.	502/117
	J	US-5,789,638 A	08-1998	Hahn et al.	585/275
	K	US-5,340,892 A	08-1994	Kuramoto, Masahiko	526/119
	L	US-5,196,490 A	03-1993	Campbell et al.	526/160
	M	US-5,721,327 A	02-1998	Santi et al.	526/133

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Silva et al. Polyhedron, 1999, 18(22), 2823-2826 (abstract only)
	V	Herrmann et al. J. Organomet. Chem., 1989, 362(1-2), C5-C7 (abstract only)
	W	
	X	 March 08, 2005

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.